

Search Notes

Application/Control No.

09/845,575

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

LAMBERT ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
709	219	8/30/2005	
707	3	8/30/2005	
709	217	12/22/2005	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
715	513	1/12/2005	
715	526	1/12/2005	
715	501.1	1/12/2005	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, US-PGPUB (see search history printout)	8/30/2005	
IEEE DataBase (see search history printout)	8/30/2005	
Portal USPTO, ACM Dig Lib (see search history printout)	8/30/2005	
USPAT, US-PGPUB (see search history printout) + Interference search	12/22/05	

SEARCHED			
Class	Sub.	Date	Exmr.
715	513 501.1 511, 517 526, 744	12/27/05	OK
707	341.10 201, 1061 102, 175 178, 2		
705	5, 14		
719	315		
345	719, 853		
709	201, 218, 328, 249		
382	173		
358	1-18		
711	122		
714	749		
717	175		
704	9		
updated on above		11/12/05	OK

INTERFERENCE SEARCHED			
Class .	Sub.	-Date	Exmr.
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